



21

Teststreifenanalysegerät

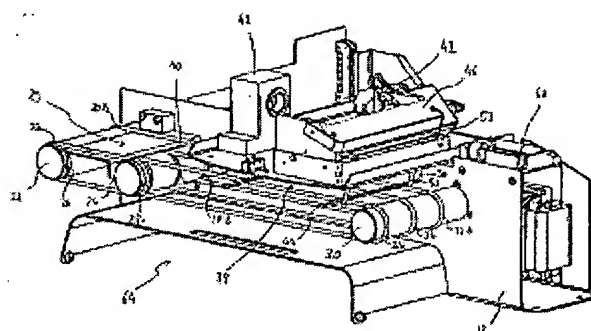
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 WO03044500 (A1)
 EP1459051 (A1)

Report a data error here**Abstract of DE10156811**

A test strip analysis apparatus comprising a housing, an insertion station for receiving a test strip to be inspected, an optical measuring unit for measuring the test strip, a transport device for transporting the test strip from said insertion station to the optical measuring unit within the reaction period required for the test strip, and an analyzing unit for evaluating the measurement of the strip, wherein the transport device comprises first and second transport sections which are interconnected through a connecting region and can be driven independently of one another, with the first transport section being capable of transporting the test strip at a higher first transport speed from the insertion station to the connecting region, and the second transport section being capable of transporting the test strip at a slower second transport speed from the connecting region to the optical measuring unit.



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